

# DDECS 2016

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IEEE international symposium DDECS16 (Design and Diagnostics of Electronic Circuits and Systems) took place in Košice, Slovakia. It's a forum for exchanging ideas, discussing research results, and presenting practical applications in the areas of design, test, and diagnosis of electronic circuits and systems. DDECS 2016 took place in Košice, the metropolis of eastern Slovakia.

Symposium was 3 days long, and contained multiple presentation sessions and single poster session. The topics, covered within frames of this symposium were: Soft Errors and Reliability, Analog Design, Digital Design, Mixed-signal Design & Test, Medical Applications, Microprocessor Test, Design for Testability, Power-aware Design, and Industrial Applications.

Three keynotes were given during the event, they were covering topics: reliability, verification and design for reliability. The interesting keynote was given by Dr. Cecilia Metra "Test and Reliability Challenges for High Performance, Nanotechnology Circuits and Systems", because it was about current unsolved problems in academia and industry. The paper, I've presented at this event was called "High-Level Modeling and Testing of Multiple Control Faults in Digital Systems".

During the social event we've visited Wine cellars of Tokaj. Friendly atmosphere, interesting topics and experienced attendees made this conference a good place to get a feedback about the research, we've been working on, and also make know other people and contacts from IT research community.

